

Search Notes

Application/Control No.

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Examiner

Emmanuel S. Luk

Applicant(s)/Patent under
Reexamination

JEON ET AL.

Art Unit

1722

SEARCHED

Class	Subclass	Date	Examiner
425	190	1/7/2006	EL
425	191	1/7/2006	EL
425	208	1/7/2006	EL
425	209	1/7/2006	EL
425	558	1/7/2006	EL
366	76.3	1/7/2006	EL
366	79	1/7/2006	EL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see EAST text search		1/7/2006	EL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search	1/7/2006	EL